

NOV 10 2004

BEST AVAILABLE COPY

COPY

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(213.003-D2-US)

In re Application of: Ye et al.

Serial No: 10/763,142

Filed: January 22, 2004

Title: Method and Apparatus for Monitoring
Integrated Circuit Fabrication

Group Art Unit: 2125

Examiner:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

I hereby certify that this correspondence is
being deposited with the United States
Postal Service as first class mail with
sufficient postage in an envelope
addressed to the Commissioner for
Patents, P.O. Box 1450, Alexandria, VA
22313-1450 on July 30, 2004

Date

Michaleo Siter
(person signing this certificate)

Michaleo Siter
Signature

THIRD INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of each
document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of these
references formally of record with the initial Office Action.

Respectfully submitted,

COPY

Date: July 30, 2004

Neil A. Steinberg
Neil A. Steinberg
Reg. No. 34,735
650-988-8079

COPY

PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 213.003-D2-US	SERIAL NUMBER 10763,142
	APPLICANT(S) Ye et al.	
	FILING DATE January 22, 2004	GROUP ART UNIT 2125

Sheet 1 of 1

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,444,637	8/1995	Smesny et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER:	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(213.003-D2-US)**

APPLICANT: Ye et al.

Filed: January 22, 2004

SERIAL NO.: 10/763,142

**TITLE: Method and Apparatus for Monitoring Integrated Circuit
Fabrication**

RECEIPT OF THE FOLLOWING PAPERS IS ACKNOWLEDGED

1. Third Information Disclosure Statement (1 page + Modified Form-PTO-1449 (1 page) + Reference cited therein)

DATE: July 30, 2004



[Check No. N/A]

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- ☐ BLACK BORDERS
- ☒ IMAGE CUT OFF AT TOP, BOTTOM OR SIDES
- ☐ FADED TEXT OR DRAWING
- ☐ BLURRED OR ILLEGIBLE TEXT OR DRAWING
- ☐ SKEWED/SLANTED IMAGES
- ☐ COLOR OR BLACK AND WHITE PHOTOGRAPHS
- ☐ GRAY SCALE DOCUMENTS
- ☒ LINES OR MARKS ON ORIGINAL DOCUMENT
- ☐ REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY
- ☐ OTHER: _____

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.